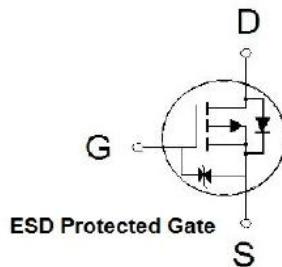
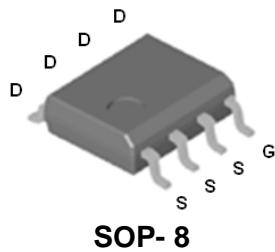


PZ2003EV

P-Channel Logic Level Enhancement Mode MOSFET

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
-30V	20mΩ @ $V_{GS} = -10V$	-8A



ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	-30	V
Gate-Source Voltage	V_{GS}	± 20	
Continuous Drain Current	I_D	-8	A
		-6.5	
Pulsed Drain Current ¹	I_{DM}	-50	
Avalanche Current	I_{AS}	-30	
Avalanche Energy	E_{AS}	46	mJ
Power Dissipation	P_D	2	W
		1.3	
Operating Junction & Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient	R_{0JA}		60	°C / W

¹Pulse width limited by maximum junction temperature.

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ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

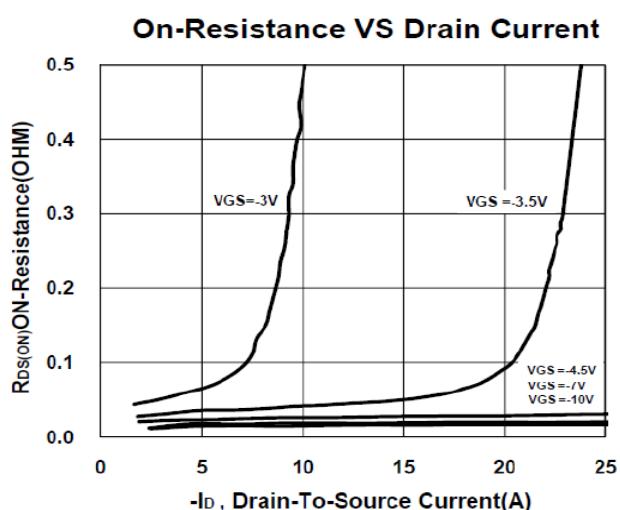
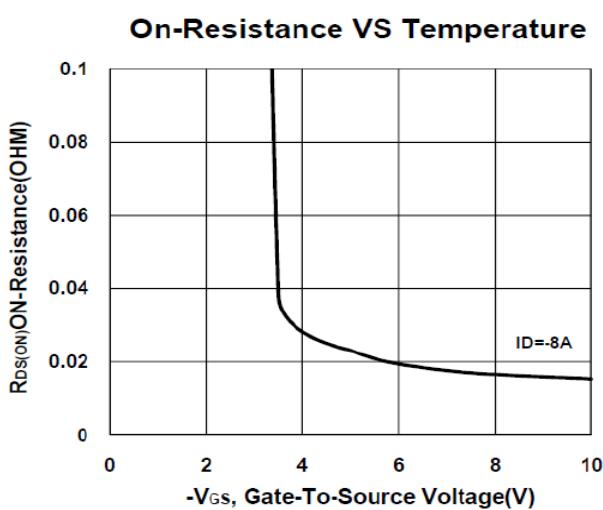
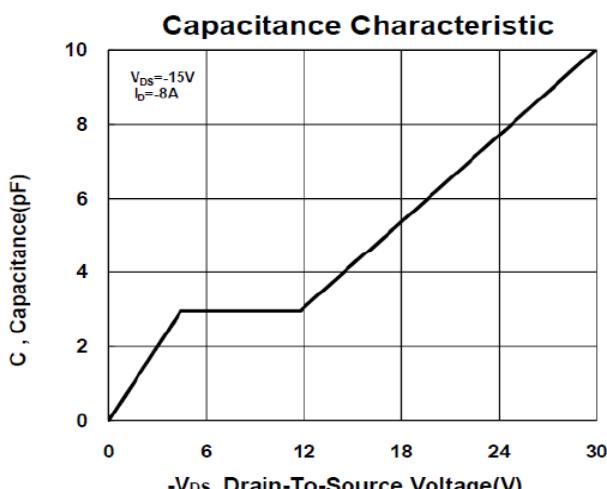
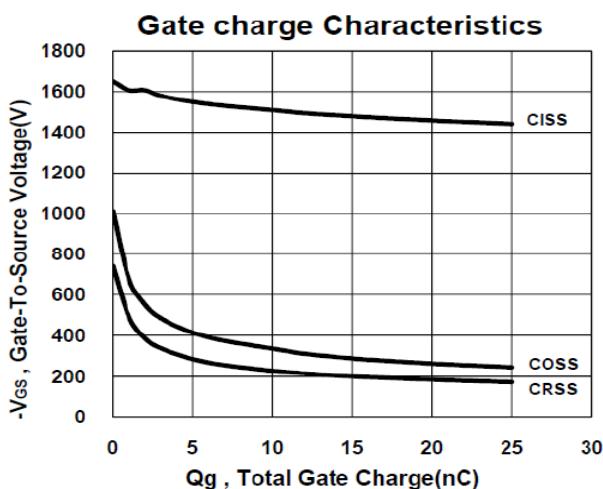
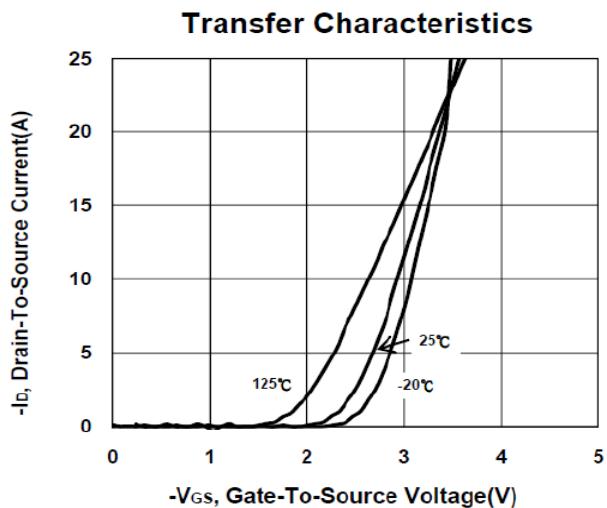
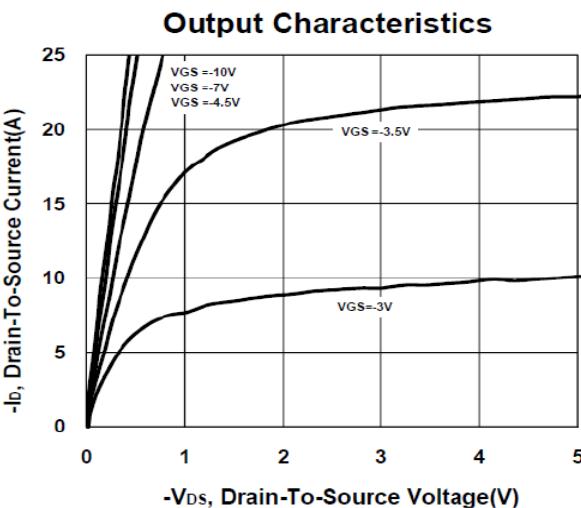
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = -250\mu\text{A}$	-30			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = -250\mu\text{A}$	-1	-1.6	-3	
Gate-Body Leakage	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 16\text{V}$			± 30	μA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = -24\text{V}, V_{\text{GS}} = 0\text{V}$			-1	μA
		$V_{\text{DS}} = -20\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 70^\circ\text{C}$			-10	
On-State Drain Current ¹	$I_{\text{D}(\text{ON})}$	$V_{\text{DS}} = -5\text{V}, V_{\text{GS}} = -10\text{V}$	-50			A
Drain-Source On-State Resistance ¹	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = -4.5\text{V}, I_D = -7\text{A}$		27	35	$\text{m}\Omega$
		$V_{\text{GS}} = -10\text{V}, I_D = -8\text{A}$		17	20	
Forward Transconductance ¹	g_{fs}	$V_{\text{DS}} = -10\text{V}, I_D = -8\text{A}$		22		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = -15\text{V}, f = 1\text{MHz}$		1500		pF
Output Capacitance	C_{oss}			293		
Reverse Transfer Capacitance	C_{rss}			207		
Gate Resistance	R_g	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 0\text{V}, f = 1\text{MHz}$		3.1		Ω
Total Gate Charge ²	Q_g	$V_{\text{DS}} = -15\text{V}, I_D = -8\text{A}, V_{\text{GS}} = -10\text{V}$		30		nC
Gate-Source Charge ²	Q_{gs}			5		
Gate-Drain Charge ²	Q_{gd}			8		
Turn-On Delay Time ²	$t_{\text{d}(\text{on})}$	$V_{\text{DS}} = -15\text{V}, I_D \geq -8\text{A}, V_{\text{GS}} = -10\text{V}, R_{\text{GS}} = 6\Omega$		20		nS
Rise Time ²	t_r			12		
Turn-Off Delay Time ²	$t_{\text{d}(\text{off})}$			48		
Fall Time ²	t_f			22		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ\text{C}$)						
Continuous Current	I_S				-8	A
Forward Voltage ¹	V_{SD}	$I_F = -8\text{A}, V_{\text{GS}} = 0\text{V}$			-1.2	V
Reverse Recovery Time	t_{rr}	$I_F = -8\text{A}, dI/dt = 100\text{A}/\mu\text{s}$		18		nS
Reverse Recovery Charge	Q_{rr}			7		nC

¹Pulse test : Pulse Width $\leq 300\ \mu\text{sec}$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

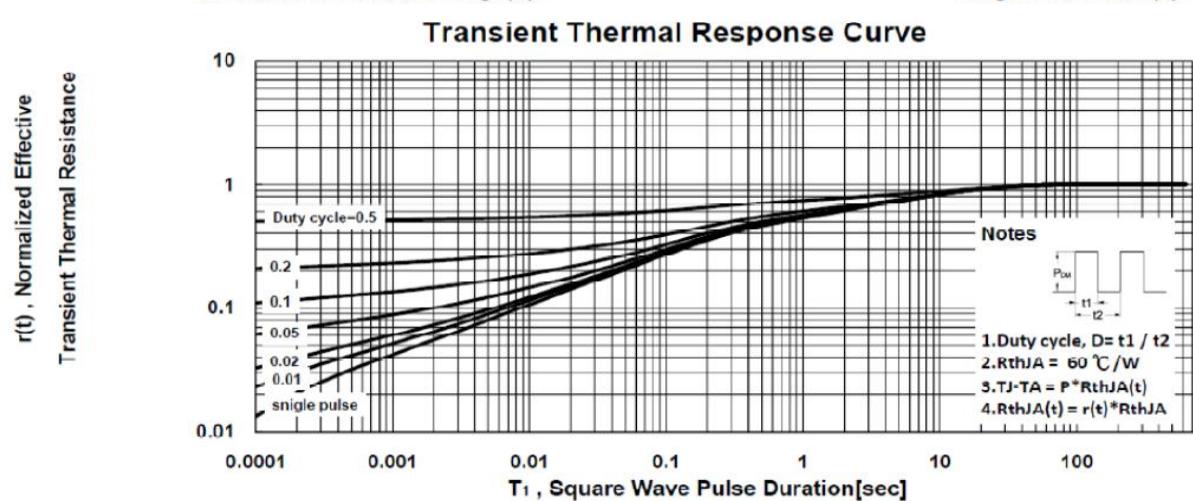
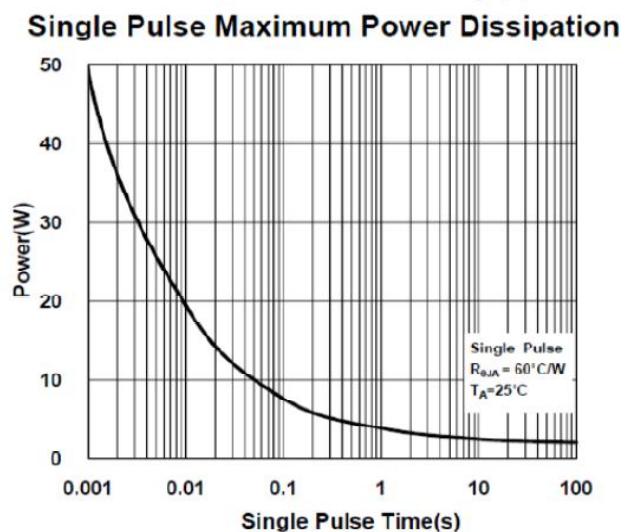
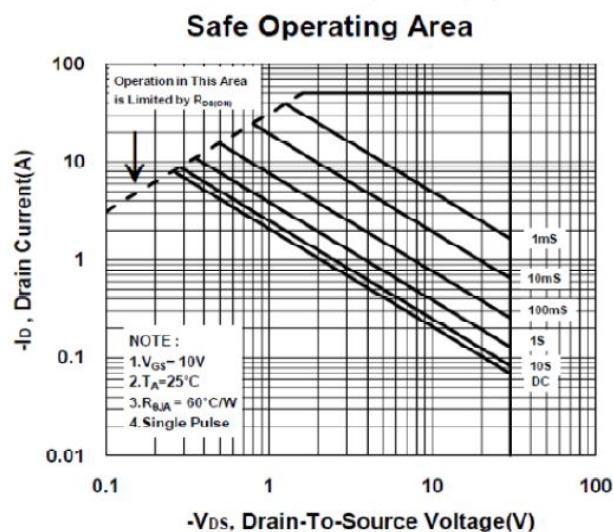
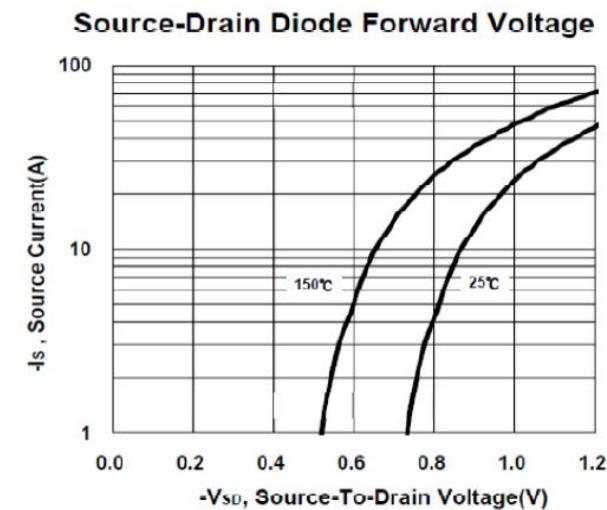
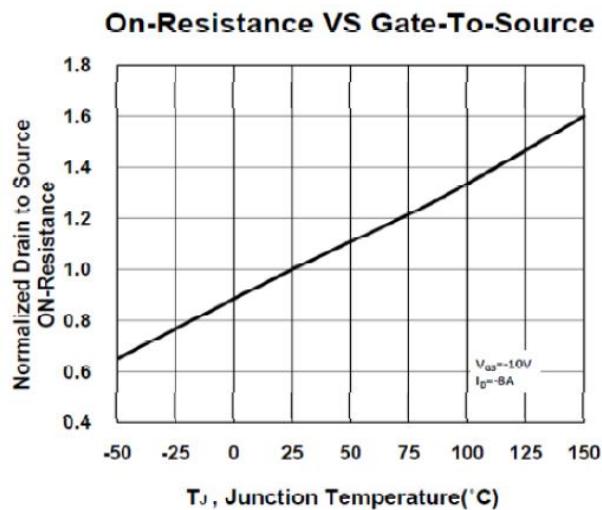
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Package Dimension

SOP-8 MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	4.8	4.9	5.0	H	0.4	0.6	0.93
B	3.8	3.9	4.0	I	0.19	0.21	0.25
C	5.79	6.0	6.2	J	0.25	0.375	0.5
D	0.33	0.4	0.51	K	0°	3°	18°
E	1.25	1.27	1.29				
F	1.1	1.3	1.65				
G	0.05	0.15	0.25				

